



INTEGRAL JEM-X

EIDP No.: IN-JX-SR-EIDP-003

Issue : 1

END ITEM DATA PACKAGE

Nomenclature: JEM-X MASK

Model - S/N: FM1

Identification No.: IN-JX-SR-DW-600

CI-Number: I 13 3000 FM

Contract No.: CICYT PI 1545

PREPARED BY J. ZARAUZ DEPT.: Quality DATE 27-03-2000

SENER Quality Assurance

REVIEWED BY J.I. RUIZ DE URIEN DEPT.: Structures DATE _____

SENER Engineer Manager

28.04.2000

APPROVED BY J. ZARAUZ DEPT.: Quality DATE _____

SENER Product Assurance

18.04.2000

AUTHORISED BY T. VELASCO DEPT.: P.M. DATE _____

SENER Project Manager

14.04.2000

ACCEPTED BY _____ DEPT.: _____ DATE _____

Customer Product Assurance

Kurt Ceyg, Project Manager, DSRi



INTEGRAL JEM-X

Section: 1 Issue: 1

EIDP No.: IN-JX-SR-EIDP-003

Nomenclature: JEM-X MASK

Model - Serial Number: FMI

DELIVERABLE ITEMS LIST

Identification No.: IN-JX-SR-DW-600

CI-Number: I 13 3000 FM

Contract No.: CICYT PI 1545

SEQ. No.	QTY.	NOMENCLATURE	DRAWING NUMBER	PART NUMBER	S/N	O. A. STAMP	REMARKS
01	1	JEM-X MASK FMI	IN-JX-SR-DW-600	--	--		
02	1	Copy of EIDP	IN-JX-SR-EIDP-003	--	--		
03	1	Special Adaptor Tool for mask integration on PLM	-----	--	--		
04	1	Transport plate assembly	IN-JX-SR-DW-410	--	--		
05	2	Optical Cubes Plastic Covers	-----	--	--		One set spare



INTEGRAL JEM-X

Section: 1 Issue: 1

EIDP No.: IN-JX-SR-EIDP-003

Model - Serial Number: FM1

Nomenclature: JEM-X MASK

Identification No.: IN-JX-SR-DW-600

CI-Number: I 13 3000 FM

Contract No.: CICYT PI 1545

LOOSE PARTS LIST

SEQ. No.	QTY.	NOMENCLATURE	DRAWING NUMBER	PART NUMBER	S/N	DEDICATED PARTS	Q.A. STAMP	REMARKS
01	12	I/F Screws LN 29950-05 12B	IN-JX-SR-DW-600	31	--	Mask assembly		Assembled
02	12	I/F Washer LN 9016-05	IN-JX-SR-DW-600	32	--	Mask assembly		Assembled
03	4	Screws M10	IN-JX-SR-DW-410	03		Transport plate assembly		Assembled
04	4	Washers 10.5	IN-JX-SR-DW-410	04		Transport plate assembly		Assembled
05	1	Plastic cover	IN-JX-SR-DW-410	--		Transport plate assembly		Assembled
06	12	Screws M4	IN-JX-SR-DW-410	07		Transport plate assembly		Partially Assembled
07	12	Washers 4.3	IN-JX-SR-DW-410	08		Transport plate assembly		Partially Assembled
08	16	Screws M5	IN-JX-SR-DW-410	09		Transport plate assembly		Assembled
09	16	Washers 5.3	IN-JX-SR-DW-410	10		Transport plate assembly		Assembled



INTEGRAL JEM-X

EIDP No.: IN-JX-SR-EIDP-004

Issue : 1

END ITEM DATA PACKAGE

Nomenclature: JEM-X MASK

Model - S/N: FM2

Identification No.: IN-JX-SR-DW-700

CI-Number: I 13 3000 FM

Contract No.: CICYT PI 1545

PREPARED BY J. ZARAUZ DEPT.: Quality DATE 27-03-2000

SENER Quality Assurance

REVIEWED BY J.I. RUIZ DE URIEN DEPT.: Structures DATE _____

SENER Engineer Manager

28.04.2000

APPROVED BY J. ZARAUZ DEPT.: Quality DATE _____

SENER Product Assurance

18.04.2000

AUTHORISED BY T. VELASCO DEPT.: P.M. DATE _____

SENER Project Manager

18.04.2000

ACCEPTED BY _____ DEPT.: _____ DATE _____

Customer Product Assurance

Kurt Cruz Project Manager, DSR1



INTEGRAL JEM-X

Section: 1 Issue: 1

EIDP No.: IN-JX-SR-EIDP-004

Model - Serial Number: FM2

Nomenclature: JEM-X MASK

Identification No.: IN-JX-SR-DW-700

Contract No.: CICYT PI 1545

CI-Number: I 13 3000 FM

DELIVERABLE ITEMS LIST

SEQ. No.	QTY.	NOMENCLATURE	DRAWING NUMBER	PART NUMBER	S/N	O.A. STAMP	REMARKS
01	1	JEM-X MASK FM2	IN-JX-SR-DW-700	--	--		
02	1	Copy of EIDP	IN-JX-SR-EIDP-004	--	--		
03	1	Special Adaptor Tool for mask integration on PLM	-----	--	--		
04	1	Transport plate assembly	IN-JX-SR-DW-410	--	--		
05	1	Optical Cubes Plastic Covers	-----	--	--		One set spare



INTEGRAL JEM-X

Section: 1 Issue: 1

EIDP No.: IN-JX-SR-EIDP-004

Model - Serial Number: FM2

Nomenclature: JEM-X MASK

Identification No.: IN-JX-SR-DW-700

Contract No.: CICYT PI 1545

CI-Number: I 13 3000 FM

LOOSE PARTS LIST

SEQ. No.	QTY.	NOMENCLATURE	DRAWING NUMBER	PART NUMBER	S/N	DEDICATED PARTS	Q. A. STAMP	REMARKS
01	12	I/F Screws LN 29950-05 12B	IN-JX-SR-DW-700	31	--	Mask assembly		Assembled
02	12	I/F Washer LN 9016-05	IN-JX-SR-DW-700	32	--	Mask assembly		Assembled
03	4	Screws M10	IN-JX-SR-DW-410	03		Transport plate assembly		Assembled
04	4	Washers 10,5	IN-JX-SR-DW-410	04		Transport plate assembly		Assembled
05	1	Plastic cover	IN-JX-SR-DW-410	--		Transport plate assembly		Assembled
06	12	Srews M4	IN-JX-SR-DW-410	07		Transport plate assembly		Partially Assembled
07	12	Washers 4,3	IN-JX-SR-DW-410	08		Transport plate assembly		Partially Assembled
08	16	Screws M5	IN-JX-SR-DW-410	09		Transport plate assembly		Assembled
09	16	Washers 5,3	IN-JX-SR-DW-410	10		Transport plate assembly		Assem bled

UNIVERSITY OF VALENCIA	MINUTES OF MEETING	INTEGRAL PROJECT
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Document Reference: IN-JX-UV-MIN-009	Date: 18th April	Issue: 1.0
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<u>SUBJECT</u>
JEM-X MASKS TRB & DRB MEETING

Present:	
Kurt Omp @ DSRI <i>Kurt Omp</i>	M. Notarnicola @ ALENIA <i>M. Notarnicola</i>
Giuseppe Sarrì @ ESA <i>Giuseppe Sarrì</i>	M. Pugliese @ ALENIA <i>M. Pugliese</i>
A. Neverla @ ESA <i>A. Neverla</i>	J. Ruiz Urien @ SENER <i>J. Ruiz Urien</i>
Victor Reglero @ UV <i>Victor Reglero</i>	J. Zarauz @ SENER <i>J. Zarauz</i>
Tirso Velasco @ UV <i>Tirso Velasco</i>	Jose Luis Gasent @ UV <i>Jose Luis Gasent</i>
Juana M ^a Rodrigo @ UV <i>Juana M^a Rodrigo</i>	Jorge Alamo @ UV <i>Jorge Alamo</i>

Documents distributed:
1. IN-JX-UV-LIS-011 (FM1) - 012 (FM2) ISSUE 1.1 CIDL
2. IN-JX-UV-LIS-013 (FM1) - 014 (FM2) ISSUE 1.0 Compliance Matrix
3.
4.

Copies of minutes to:	
G. Sarrì @ ESA	J. Ruiz Urien & J. Zarauz @ SENER
K. Omp @ DSRI	M. Notarnicola & Pugliese @ ALENIA

Minutes taken by: Kurt Omp & Juana M ^a Rodrigo

9:15

WELCOME BY VICTOR REGLERO

ACTION

Prof. Reglero thanks to all attendants to visit U. of Valencia for holding the DRB Jem-X Mask Meeting.

These subassemblies are the second flight configuration hardware finished by GACE. Five years ago, the group was involved in the LEGRI Instrument on board on MINISAT-01 satellite.

Now as part of the JEM-X Consortium, GACE people is very happy to conclude ten years of work in the development, design, manufacturing and testing of the Coded Masks.

This Instrument is very interesting because cover the field of application from X-Ray to γ -Ray.

9:20

ADOPTION OF AGENDA

O.K.

9:25 FM ACTIVITIES REVIEW

ACTION

FM JEM-X Masks activities have been developed during last year 12 months from the MASK CDR Meeting date.

Manufacturing phase has done in a period of six months and after one month for integration and four months for testing and documentation.

9:30 ACCEPTANCE TEST RESULTS

Tirso Velasco presents all documents dedicated to the FM Masks tests (procedures and reports) in a list which shows documents including in the EID-P and others availables in GACE facilities.

MASS.

ACTION.

FM1 5.6335 + 0.0002 Kg

FM2 6.0853 + 0.0002 Kg

QM 5.8085 + 0.0002 Kg

} $\Delta m \approx 0.5 \text{ Kg}$

Differences between FM1 & FM2 are due to the different plates thickness.

FM1 0.43 mm \pm 0.01 mmFM2 0.56 mm \pm 0.02 mm} $\Delta m \approx 0.5 \text{ Kg}$ stimated mass

1.614 Kg

2.101 Kg

FM2 Deviation from mass budget is reported in the Non Conformance Report referenced: IN-JX-SR-NCR-007.

The ESA comment number four to the FM EID-P Documentation can be considered closed.

Electrical Check:

All values are within the requirement
($< 5 \text{ m}\Omega$)

VIBRATION TEST

Tirso Velasco explain the test conditions which are according to the Assembly Integration and Test Plan (A.I.T. Plan)

Ignacio Ruiz Urien present a table which summarises the results of the test and in the second slide the notching philosophy is explained

Vibration Test Sequence Req:

- Resonance Survey: 0.5g 5-2000 Hz
Sweep Rate of 2 oct/min
- Sinusoidal Vibration: acceptance level 4 oct/min
- Resonance Survey: 0.5g 5-2000 Hz 2 oct/min
- Random Vibration: -6.5 dB (-10dB from QM Level) 30 sec.
- Random Vibration: Acceptance level (1 minute)
- Resonance Survey: 0.5g 5-2000 Hz 2 oct/min
- " after thermal cycling: 0.5 5-2000 Hz 2 oct/min

ACTION

Accelerometers configuration was the same that the QM configuration

ACTION

Axial 1^{er} frequency $FM1 = 210 \text{ Hz}$

$FM2 = 198 \text{ Hz}$

QM = 197 Hz

this frequency correspond to fundamental mode of the Mask.

2nd frequency $FM1 = 444 \text{ Hz}$

$FM2 = 500 \text{ Hz}$

STM = 450 Hz

Notching in axial is showed in a dedicated table in Mr. Ruiz Urien slide presentation (Annexe 2)

First frequency is higher in the FM1 due to the string back contribution and in the second mode is more important the W plate contribution to the value

Accelerations obtained are quite similar to the axial accelerations obtained during the STM/QM Test Campaign \Rightarrow the results are according to the models and are into the requirements. said Mr. Ruiz Urien

Random Vibration

Small differences could be appreciate comparing the FM1 & FM2.

Lateral notching is applied due to quasi-static loads and with ESA agreement in order to limit the loads on W membrane.

Mr. Sarri, explain the results of the mechanical test in a satellite level. Comparing the results of the FM Masks test campaign with the satellite results, ESA has found a potential problem.

Mr. Ruiz Urien explain that the accelerometers used in a satellite are mounted on the panels and they received signals coming for all parts.

ACTION

The values measured on the panels are not the mask levels inputs. The mask number 7 accelerometers covers the satellite range: the largest peak ~~value~~ ^{peak} is more higher than satellite peak ~~value~~ in axial mode which is the critical.

(Accelerometer number 7 in the QM test campaign comparing with the level satellite curve.)

After a discussion on the accelerometers positions, loads induced on the masks by the ~~bus~~ ^{PLM} etc. Mr. Sarry explain

that the goal is to verify that FM masks ~~are~~ ^{have} the same workmanship as ~~is that~~ QM Mask. After

a review of the FM test results ESA/ALENIA have found that lateral response of the accelerometer number four is not the same than accelerometer number four for the QM Mask.

Mr. Sarry explains that these differences have been found in accelerometers number 4y & 8y.

ACTION

This statement is not agreed by Alenia/ESA

Mr. Ruiz Orién explains that INTA has changed the software acquisition and the accelerometer position could be little different from QM position because the accelerometer number four is mounted on the 20 mm area in the strong back.

ACTION

E.S.A. position on this ^{workmanship} matter is consider that FM & QM could be different and this is implicated in particular by ~~due to~~ f_y & f_x accelerometers results.

GACE, Prof. Reglero, are not in agreement and he consider that only after a detailed study of the situation could be demonstrated that two systems (FM & QM) are not the same, ~~if any~~. All the rest of values are according to the QM test results.

For GACE the important data is the acceleration and for ESA/SENIA ~~the important~~ both ~~value~~ ~~is~~ the amplification and acceleration value are to be considered.

GACE/SENER opinion is that FM & QM systems are similar and we have not found systematic differences between FM & QM.

A summary positions on vibration matter is:

ACTION

ESA/ALENIA think that a possible difference exists between STM & FM masks. This difference may be critical w.r.t. to the sk. level FM test of the Mask.

Considering the higher levels were measured on sk. STM w.r.t. to the mask qualification level, ~~mask can full confidence~~ must be achieved that ~~be accepted only if~~ no difference exists ~~is demonstrate~~ between STM/QM and FM.

SENER/U.V. position is that levels measured on the sk. are not only the input but already include the output of the mask, therefore the qualification of the mask fully cover the sk. test level in the fundamental frequencies.

ACTION

Conclusions on the JET-X mask vibration issue:

1. Masks are accepted as far as the vibration test results are concerned.
2. Aleuia will review in detail the QH/STN mechanical test results in order to confirm confidence on the similarity of STN and FTS masks. All data will be provided by UV.
3. In performing the above, support from UV/Senor will be given to Aleuia (Teloron and/or meeting)
4. If needed ESA/Aleuia may ask a delta vibration characterization on STN/QH mask.
5. UV/Senor will support the mechanical tests at S/C level.

12:30 THERMAL CYCLING

ACTION

Only thermal cycling was performed according to TRR agreements; the test was performed with no major problem.

SEVER P.A. Manager issued a NCR, ref. (IN-JX-SR-NCR-006 because during a short time (30 min.) the softw. acquisition was fault.

Comment number 2 of ESA is closed.

12:35 ALIGNMENT & POSITIONING

Presented by Víctor Reglero. He explains that two main conclusions are:

- pixel position and size are one order better than requirements
- the position of the pixels does not change if the mask is free or bolted configuration.

After to measure 230 pixels (in the manufacturer workshop (200) and in the INTA facilities (30) for checking that they have not changed)

The results of the 30 pixels measured on INTA facilities shows that $\sigma = 0.005$ mm in FM1 & FM2 with a maximum deviation of 0.010 mm < than ± 0.05 mm required.

The pixels size uncertainty, after to measure 400 pixels (200 pixels by ur code), is ± 0.005 mm : ten times better than specified. And the pixel center position on the YZ plane is 0.04 mm : 7 times better than specified.

The coded flatness, free configuration on the marble 3D machine, is 0.05 mm respect to the average of the X-axis values on the interface points.

The deviation angle between the code and i/f plane is 6 arc. sec. And this answer the Mr. Ømo comment about flatness.

The comment number 5 (Mr. Sarry comments to JEM-X Masks EIDP) is closed.

ACTION

Measurements with theodolites at INTA before and after test campaign, with the masks bolted and free, give following maximum differences:

FM1 : max +3" min -3"

FM2 : max +11" min -7"

This answer the ESA comment number 5 because the 55" measured is for the 3D machine. With theodolites the precision is better like shows the above mentioned table.

Cubes do not move before and after test; the optical cubes mounting is stiffness. Error in theodolite system is 1 arcsec.

The Optical Cube position does not change (+5 arc. sec) when the Mask is bolted according to the integration procedure.

For the FM integration activities, GACE required to the ALENIA integration team that torqued applied will be 6 N.m in the interface holes.

ACTION

For JEM-X Instrument collaboration, the position between mask and detector plane has to be around 15", said

Prof. Reglero. A difference of 0.01-mm in the interface plane should not be critical for the instrument alignment.

ALENIA representative, Mr. Plugliese, exposes that they not consider possible to assure the torque applied during the integration activities. GACE will provide a special tool for torquing the critical interface screws (difficult to access in some points) and will support ALENIA during this operations because GACE team will be present during IBIS and Jem-X MASK integration on the s/c.

Comment number 7 is closed too.

ALENIA will sent the STM MASK integration procedure to UV for comments.

Action

ALENIA

→ CLOSED

Comment number 3 of ESA: interface holes positioning \Rightarrow Ti Ring manufacturing drawing requirement is 0.05 and interface holes position req. in the interface drawing is 0.1. The NCR affects a the manufacturing drawing.

13:30 APPLICABLE EID-P DOCS. REVIEW

ACTION

1. Items being delivered

- Jem-X Mask FM1 & FM2 including
- optical cubes for both assemblies
- copy of EIDP docs (FM1 & FM2)
- special adaptor tool for integration (2u)
- transport plate assembly (2u)
- Optical cubes plastic covers for 2 assemblies
- 1/4 screws and washers for 2 assemblies + plus
- one mask plastic cover (2u)

2. CONFIGURATION STATUS

CIDL

A new FM1 & FM2 CIDL issue is delivered during the meeting and a new FM1 & FM2 Compliance Matrix for the JEM-X Coded Mask.

FM1 CIDL : IN-JX-UU-LIS-011 Iss 1.1

FM2 CIDL : IN-JX-UU-LIS-012 Iss 1.1

Compliance Matrix FM1 : IN-JX-UU-LIS-013 Iss 1.0

" FM2 : IN-JX-UU-LIS-014 Iss 1.0

} *

DSRI has delivered to UU the EID-B

Issue 5.2 during meeting

Matrix is a summary of all the parameters

Change Request (pending)

NoNe

Request for Waiver:

- ~~No open~~ UV will sent to ESA all RFW (1,2,3,4) for ESA closure.

- IN-JX-UV-RFW-003: the RFW concerning to the notching philosophy during QM test campaign is still open. ESA will formally ~~close it~~ process it.

3: COMPLETION & RESULTS of TEST PROGRAM

- IN-JX-UV-RFW-004: OK. Only cycling no vacuum thermal during TWT.

* ⇒ We could consider test campaign is closed
 Test program was completed with the concern referenced above.

4. Non Conformances

All NCRs are closed. No major NCRs during FM.

002 → W roughness out of tolerance and the plate has been used as is.

004 → Holes ϕ 4.5. OUT ⇒ repaired and closed.

005 → The i/f holes positioning error is related to the ring manufacturing drawing and not to the

ACTION

ACTION

UV

ACTION

ESA

interface precision. The NCR not affect to the s/c.

004 and 005

ACTION

006 → Thermost Cycling data acquisition software fault during 30 min. closed

007 → FM2 Mass Over Budget Accept and close

5. Open or Deferred work

None

6. Temporary Removals or Installations

Removal and segregation of the 1/4 screws

Removal Optical cubes covers

7. RESIDUAL HAZARD and

Radiative sources are not included and point 7 is not applicable ..

8.13. PACKING ; HANDLING & INTEGRATION PROC.

All activities, including integration, are explained in the Packing, Handling & Integration Procedure (IN-JX-USR-PRO-001 Issue 3.0).

~~ESA will verify that two masks will have protected with dedicated covers when they will be mounted on the s/c.~~

Jew-X Protection cover is foreseen when the subassemblies will be mounted (see Mr. R. Timm communication to UO after Mask TRR Annex number 3).

UO will support to ALENIA during integration activities. An Integration Plan could be defined between UO/SENER & ESA Project office.

Open Point

- Identification Plates Label for each subassembly are on going.

- Lot 1 includes the optical cubes covers

ACTION

~~ACTION~~
~~ESA~~

ACTION

ESA
&
UO

- Section 4 includes the minutes.	ACTION
- Section 6 complet the log sheet	
- Section 7 CIDL FM1 and FM2 new issue (delivered during meeting)	
- Section 8 I/F drawing will be issue with the dates of the rest of Instrument or SIC A Change Notice has been issue according to this drawing (IN-JX-SR-DW-100) in order to remove the "TBD" dates (for instance type of material of the interface, surface treatment ect)	<u>ACTION</u> SENER & ALENIA

10. EIDP

The EIDP is available and complete with the updates identified in this MOP.

11. INSPECTION of HW to be delivered.

The two semi-X masks were inspected in the 1000 clear room.

12. STATUS of SHIPPING preparation and schedule

The masks are ready to be shipped with one week notice. They will be kept in storage at UV until further notice.

The masks are accepted by DSRI / ESA / Alesia for the purpose of this DRB.

Attention is to be paid to the activities listed in page 10 of this MOP.

ACTION